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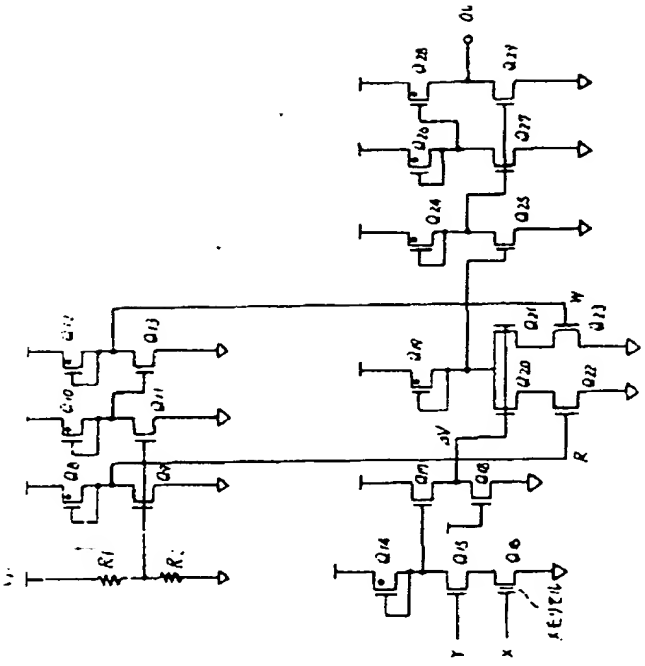
TITLE : PROGRAMMABLE READ ONLY MEMORY



ABSTRACT : PURPOSE: To easily detect defective bits at room temperature in a short time, by selecting threshold values different between the normal operation mode and each test modes, and reading out the memory content.

CONSTITUTION: A MOS transistor (TR) Q_{16} out of TRs Q_8~Q_{29} has a floating gate. Through the resistor ratio of R_1 to R_2, a gate voltage in turning Q_9, Q_{11} off at V_p=5V and that turning on the Q_9, Q_{11} at V_p=25V at test are produced. Normally, the readout from a memory cell is determined with the threshold value of the Q_{20}, and the sense output is outputted to an output terminal OUT via the Q_{25}, Q_{27} and Q_{29}. At test, the readout from the memory cell is determined with the threshold value of the Q_{21} and the sense output is outputted to an output terminal OUT via the Q_{25}, Q_{27} and Q_{29}.